

## PATENT ABSTRACTS OF JAPAN

(11)Publication number : 09-218091

(43)Date of publication of application : 19.08.1997

(51)Int.Cl.

G01J 3/02

(21)Application number : 08-021572

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(22)Date of filing : 08.02.1996

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## (54) DIODE ARRAY SPECTROPHOTOMETER

## (57)Abstract:

PROBLEM TO BE SOLVED: To secure a diffraction grating thermally and mechanically to an inlet slit and a diode array by providing an inlet slit unit, a diffraction grating, a diode array, a casing for determining the relative position of inlet slit and diode array, etc.

SOLUTION: The diode array spectrophotometer comprises an inlet slit unit, a diffraction grating 4, a diode array, a casing 1 for determining the relative position of inlet slit and diode array having a truncated conical opening 7, and at least three filling elements arranged between the outer faces of a rotary grating holder 2 having tubular sleeve outer face. This structure can secure a diffraction grating thermally and mechanically.

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## LEGAL STATUS

[Date of request for examination]

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's  
decision of rejection]

[Date of requesting appeal against examiner's  
decision of rejection]

[Date of extinction of right]

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